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Measurement of Transport Lifetime in a Cuprate Superconductor

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We report measurements of the phase of the conductivity, $\phi_\sigma \equiv arg(\sigma)$, in the normal state of a $Bi_2Sr_2CaCu_2O_{8+\delta}$ (BSCCO) thin film from 0.2-1.0 THz. From ϕ_σ we obtain the time delay of the current response, $\tau_\sigma \equiv \phi_\sigma/\omega$. After discovering a systematic error in the data analysis, the extracted τ_σ has changed from that reported earlier. The revised data is shown in the sole figure below. Analysis and discussion of these data will follow.

74.25.Gz, 74.25.Nf, 74.25.-q, 74.72.Hs

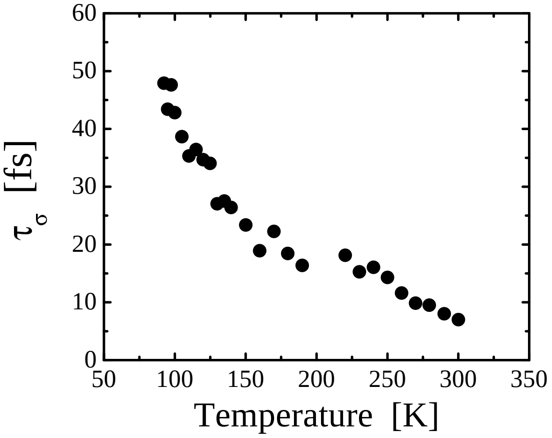

FIG. 1. τ_σ plotted versus temperature as black circles. The error bars are the standard deviation in τ_σ obtained from 40 repeated one minute scans taken at room temperature.

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